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document 7 of 17 Order Document

INSPEC - 1969 to date (INZZ)

# **Accession number & update**

5334435, B9609-7260-058; 960730.

### Title

Pixel defect tolerant design for complete repair of TFT-LCD.

### Author(s)

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### **Author affiliation**

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### Source

Proceedings of 1994 International Workshop on Active-Matrix LCDs (AMLCD), Monterey, CA, USA, 10-13 Oct. 1994.

Sponsors: SID, Advisory Group on Electron Devices, IEEE Electron Devices Soc.

In: p.436-9, 1994.

# **Publication year**

1994.

### Language

EN.

# **Publication type**

CPP Conference Paper.

### **Treatment codes**

P Practical.

### Abstract

Based on a study of the visibility of repaired pixels, we propose a new concept of pixel design rule which enables complete repair of the redundant pixel structure. (2 refs).

### **Descriptors**

field-effect-integrated-circuits; liquid-crystal-displays; semiconductor-device-reliability; thin-film-transistors.

### Keywords

pixel defect tolerant design; TFT LCD repair; redundant pixel structure.

# **Classification codes**

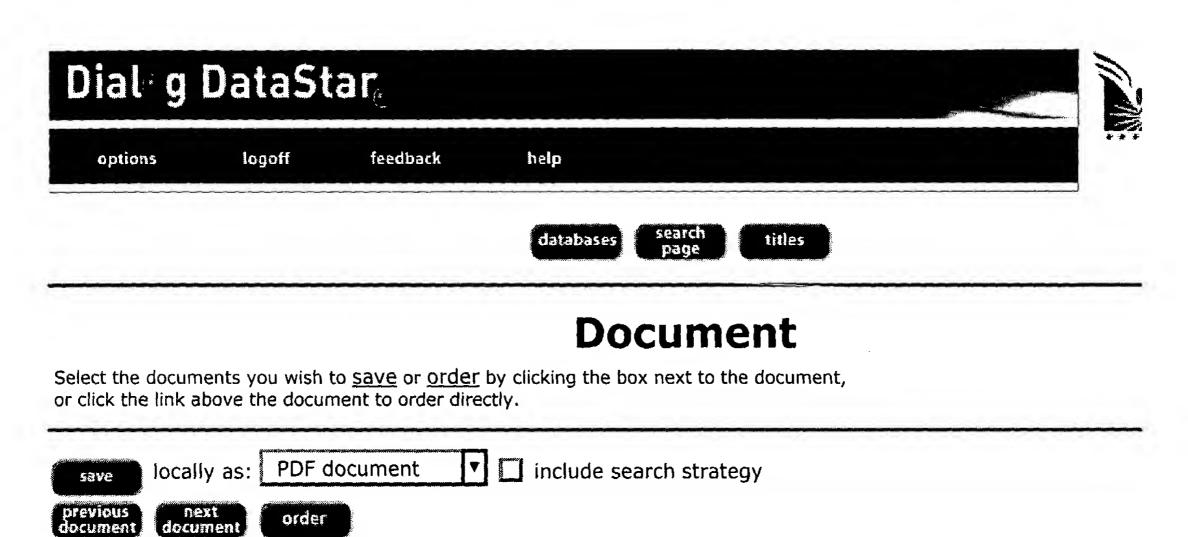
B7260	(Display technology and systems).
B4150D	(Liquid crystal devices).
B0170N	(Reliability).
B2560R	(Insulated gate field effect transistors).
B2570H	(Other field effect integrated circuits).

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5296172, B9607-7260-038; 960618.

order

Title

**Pixel-defect-tolerant** design based on visibility for TFT-LCDs.

Author(s)

document

Nakai-Y; Akiyama-M; Ikeda-M; Suzuki-K.

### Author affiliation

Mater & Device Res Labs, Toshiba Res & Dev Centre, Yokohama, Japan.

### Source

Journal-of-the-Society-for-Information-Display (USA), vol.4, no.1, p.25-31, April 1996., Published: Soc. Inf. Display.

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# **Publication type**

J Journal Paper.

### **Treatment codes**

P Practical; X Experimental.

### Abstract

The **repair** of pixel defects on TFT-LCDs, which is generally carried out with laser processing or by adopting a redundant structure, is very effective for high-yield production. However, repair may result in abnormal pixel performance, usually due to the asymmetry of the applied pixel voltage. In this study, based on consideration of the dependence of the threshold contrast on the background luminance, the authors are able to determine the visibility of a repaired pixel. As a result, good agreement between measured and calculated visibility was obtained. Based on these results, we have proposed a new pixel design rule which enables complete repair of pixel defects that cannot be detected by the human eye. This design can also suppress the reduction of the aperture for TFT-LCD panels. Furthermore, we demonstrate a new redundant structure which reduces the change in pixel

performance after **repair** to a lower level than is attainable with any other reported technique. (5 refs).

# **Descriptors**

liquid-crystal-displays; thin-film-transistors; visibility.

# Keywords

TFT **LCD**; pixel **defect** tolerant design; pixel defects **repair**; abnormal pixel performance; threshold contrast; background luminance; repaired pixel visibility; pixel design rule; aperture reduction suppression; redundant structure; pixel voltage shift; high yield production; delta filter arrangement; Weber's law.

# **Classification codes**

B7260	(Display technology and systems).
B4150D	(Liquid crystal devices).
B2560R	(Insulated gate field effect transistors).
B2220E	(Thin film circuits).

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